Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/565,876	SHIN, HEE-SEOK
Examiner	Art Unit
Thanh-Tam T. Le	2839

SEARCHED						
Class	Subclass	Date	Examiner			
439	260	6/21/2007	TL			
	495					
	566					
	570					
		:				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
SAME AS	ABOVE	6/21/2007	TL	
			i	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
TEXT SEARCH	6/21/2007	TL		
	-			